When is CAN the weakest link? A bound on Failures-In-Time in CAN-Based Distributed Real-Time Systems

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Max

Harsh environments

- Spark plugs
- Hard radiation
- High-power machinery

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Electromagnetic Interference (EMI)

- → Bit-flips in the hosts
 - ... and in the network

Harsh environments

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EMI-induced transient faults

Manifest as program-visible failures

Transmission failures (faults on the wire)

Commission failures

(bit-flips in the memory buffers)

Crash failures (due to fault-induced exceptions)

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Tolerated by **error detection** and **retransmissions**

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Tolerated by **error detection** and **retransmissions**

Tolerated by active **replication of tasks** on independent hosts

- How to decide the **best replication strategy**?
 - Is Triple Modular Redundancy (TMR) enough? or is Quadruple Modular Redundancy (QMR) required?
 - Would you replicate only the high-frequency tasks? or only the high-criticality tasks?

For tolerating retransmissions-induced delays

- → (Ensure no deadline violations)
- The more slack, the better!

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versus

Active replication of tasks **Reduced slack** in the schedule

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versus Active replication of tasks

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For tolerating retransmissions-induced delays

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How to statically determine the **optimal replication factor?**

This Work

For CAN-based distributed real-time systems...

• Probabilistic analysis

Quantify the replication vs. retransmissions tradeoff







The CAN-based system is just one component in a safety-critical system...



What if the UAV has **strict weight constraints**?

- and you can either add the heat sink or the additional ECUs
- How do you decide the **best choice**?

Failures-In-Time (FIT) Rate

Expected #failures in one billion operating hours

➡ e.g., 1M UAVs flying for 1K hours each

lable 1 <mark>. FIT Rat</mark>	e Calculations fo	r AFCT-57J7ATPZ							
			Temperatu	re Factor @ 40°C		1			
Reliability Prediction Based On		Stress Factor at 50%		1					
Telecordia SR-3	32 Issue 2 - Parts C	ount Method	Environme	ntal Factor		1			
Component		Telecordia Information/ Data Source	Quantity	Component Base Rate (FITs)	Quality Factor	Total Component Failure Rate (FITs)	_	FAILURE RATE	
DFB Laser		Avago Data @ 40 °C	1	20.0	0.8	16.0	HRS	90°C & 60% UCL	~
Monitor PIN		Photodiode	1	7.7	0.8	6.2	0°C		
I OG PIN		Photodiode	1	7.7	0.8	6.2		FITs	
Capacitors		Fixed Ceramic	27	0.2	1	5.4	105.10	(note a)	1 that
Resistor		Thick Film	21	0.51	1	10.7	HOE+0	3/	stem operation
hermistor		Thermistor	1	2.10	1	2.1	DE+U	30	aintermittent
errite Chip (In	ductor)	Power Filter	14	2.30	1	32.2	12E+0	15 18	25 totion
MOSFET		Supplier Info: On Semiconductor	1	4.00	1	4.0		10	tation.
EPROM		2 Kbit CMOS	1	6.40	1	6.4			ncern A sunn
DAC		Supplier Info: National Semiconductor	1	6.00	1	6.0			urely and caus
Post-Amp IC, C	iennum 16QFN	Assume: (91 - 170 Transistor)	1	23.00	1	23.0)		sential.
aser Driver IC		Supplier Info: Vitesse	1	6.4	1	6.4	ALEN	T FAILURE RATE	@
Processor		Supplier Info: Atmel	1	28.0	1	28.0	HRS	90°C & 60% UCL	and now it can
Connector		PCB, Edge / Multi-Pin	20	0.130	1	2.6	0°C		
			Total	Module Failure Rate	@ 40 °C (FIT	s) 157.70		FITS	
							16E+0	37	22
ITs at other he procedure nergy, Ea, o emperature amperatures able 2. FIT ra	temperatures of Telcordia of 0.35 eV to factor π_T . Tabl for the transce tes at different elcordia Parts Co	can be derived following SR-332, assuming activation determine the component e 2 shows FITs at different ver. operating case temperatures, unt Method	The limita Count Me rates are n may not l and that environme obtained	tions of the FIT thod include the nostly obtained f be exhaustive fo the results are ental stress tests. from the Parts	prediction fact that t rom Telco or state-of- independe Neverthel Count N	based on the Parts he piece part failure rdia database, which the-art piece parts, ent of true module less, the information Method is a useful	16E+0 71E+0 30E+0	15 37 15 33 15 36 16 9	elated term that nee is the amount of tim ate in its intended idoes not necessaril some applications a short service life.
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FIT rates are widely used in the industry

Failures-In-Time (FIT) Rate

Expected #failures in one billion operating hours

e.g., 1M UAVs flying for 1K hours each



Table 2. FIT rates at different operating case temperatures,following the Telcordia Parts Count Method							
T _{case} (°C)	FITs	MTBF (Hours)					
25	82	1.22E+07					
40	158	6.34E+06					
50	236	4.24E+06					
60	344	2.91E+06					
70	490	2.04E+06					
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Failures-In-Time (FIT) Rate

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FIT rates are widely used in the industry

When is the CAN-based distributed real-time system the weakest link in the system?

490

This Work

For CAN-based distributed real-time systems...

• Probabilistic analysis

Quantify the replication vs. retransmissions tradeoff

• FIT rate analysis

Builds upon the proposed probabilistic analysis

Overview





Evaluation

Transmission failures (faults on the wire)

Commission failures

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Probability that each message is omitted / corrupted / retransmitted

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Probability that each message is omitted / corrupted / retransmitted

We do not consider **software defects**...









with Task Replication



with Task Replication


Aggregating the replicated messages



How & when to compute OUT from multiple copies of M?

Aggregating the replicated messages



How & when to compute OUT from multiple copies of M?

- Case 1: Synchronous Systems
 - Common global time base
 - e.g. majority value at the absolute deadline

Aggregating the replicated messages



How & when to compute OUT from multiple copies of M?

- Case 1: Synchronous Systems
 - Common global time base
 - e.g. majority value at the absolute deadline
- Case 2: Asynchronous Systems
 - No global time base
 - e.g. majority value after "enough" copies have been received

Overview



Model



Analysis



Evaluation

The Larger Picture...



The Larger Picture...



Objectives:

- ► A good replication strategy for the CAN-based system
- Compare the reliability of the CAN-based system with other components in the safety-critical system

The Larger Picture...



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- ► A good replication strategy for the CAN-based system
- Compare the reliability of the CAN-based system with other components in the safety-critical system

Solution: FIT rate analysis

Using the probabilistic analysis

FIT rate of the CAN subsystem





Lower Bound on the Probability of Successful Transmission of M₁

















Network faults	
Host faults	

Host and network faults follow a **Poisson distribution**

Probabilities that each message:

- retransmitted due to transmission failures
- omitted due to crash failures
- corrupted due to commission failures

Mean Time Between Failures MTBF₁ Probability Density Function f₁(t)

Lower Bound on the Probability of Successful Transmission of M₁

















Overview





Evaluation

Mobile Robot Workload*

Task Name	Length (bytes)	Period (ms)	Deadline (ms)
MotorCtrl	2	2	2
Wheel1	3	4	4
Wheel2	3	4	4
RadioIn	8	8	8
Proximity	1	12	12
Logging	8	240	240

Broster, Ian, Alan Burns, and Guillermo Rodriguez-Navas. **"Comparing real-time communication under electromagnetic interference."** Real-Time Systems, 2004. ECRTS 2004. Proceedings. 16th Euromicro Conference on. IEEE, 2004.

Mobile Robot Workload*

Only the **MotorCtrl task is replicated** (#replicas vary from 1 to 9)

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Evaluation

- Assess the proposed FIT rate derivation
 - Comparison with results from CAN bus simulation

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- Assess the proposed FIT rate derivation
 - Comparison with results from CAN bus simulation
- Is the FIT rate analysis too coarse-grained?
 - Analysis for various fault rates





#Replicas of MotorCtrl Task







FIT Rate Analysis of the CAN Subsystem

Lower means better reliability of the CAN subsystem!
















Summary

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Find the best replication strategy for CAN-based systems



Summary

Find the best replication strategy for CAN-based systems



Compare reliability of the CAN-bus subsystem in the context of the larger safety-critical system



Future Work

- More complex system models
 - CAN-based systems bridged together
 - Sporadic DAG models

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- http://www.mpi-sws.org/~bbb/projects/schedcat